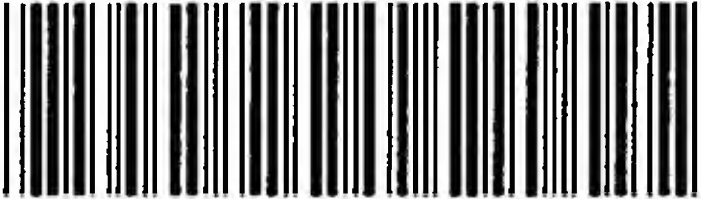


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/709,054	CHANG ET AL.	
	Examiner	Art Unit	
	Eric B. Chen	1765	

SEARCHED			
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Inventor search (PALM)	1/5/2006	EC
EAST (all databases) (text search only)	1/5/2006	EC
252/79.1-79.4; 134/2,3; 438/745,754 216/105,106 (text search only) (consulted B. Tran, AU 1765)	1/5/2006	EC